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| Application/Control No. | Applicant(s)/Patent und Reexamination | der |
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| 10/539,334 | ARTHANARI ET AL. | |
| Examiner | Art Unit | |
| Suchin Parihar | 2825 | |

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| EAST Text Search US-PAT, US-PGPUB, EPO, JPO, DERWENT, IBM-TDB (See Attached History) | 5/16/2006 | SP |
| IEEE Xplore Search (See Search History) | 5/16/2006 | SP |
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